

# CHEM 524 -- Course Outline (Part 10) – Signal to Noise —2013

For html of 2005 notes with linked figures, [click here](#)

## VII. Signal to noise considerations (*Text - Chap. 5*)

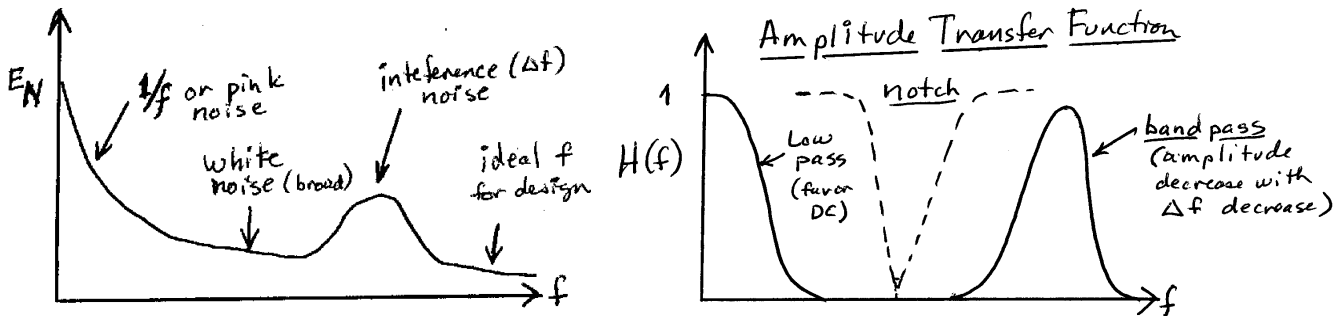
### A. Noise definitions:

- Average signal of several measurements:  $\bar{E} = \sum E_i/n$
- Standard deviation (rms excursion from mean):  $E_{rms} = \sigma_E = [\sum (E_i - \bar{E})^2/(n-1)]^{1/2}$
- random -- non-correlated to other aspects of measurement
- fundamental -- intrinsic to detection method or to photon flux
- chemical -- errors in sampling

### 1. Types

- white (Gaussian), ubiquitous to light fluctuation, random at all detection frequencies can be intrinsic to light (shot noise  $\sim n^{1/2}$ ) or detector (constant or dark noise)
- pink (1/f), -- diode detectors (e.g. MCT) show this, often become constant at  $\sim 1$  kHz
- interference (at f) – could be many things, e.g. line frequency, radio stations, neighbors
- flicker ( $\sim$ signal) – typically chemical or due to instrument stability issues

a. evaluate by understanding [noise power spectrum](#) – particular to experiment/instrument



b. use to design modulation or detection scheme – choose optimal frequency to operate

c. [Amplitude transfer function](#) (book: Table 5-1, Fig. 5-4)

- mathematical representation of device efficiency as function of frequency:  $H(f) = E_{out}/E_{in}$
- band pass:  $\Delta f = \int |H(f)|^2 df$  -- frequency range with attenuation  $< 3$  dB or  $H(f) < 0.707$
- effect on noise:  $\sigma_E^2 = \int P(e)|H(f)|^2 df$  where  $P(e)$  -- density spectrum
  - -- white noise:  $\sigma_E^2 = P(e)\Delta f$  - since  $P(e)$  const
- time constant -- low pass at  $f = 0$  -- DC/stability trade off
  - wait  $5\tau$  to make measurement, *rule of thumb*:  $\tau < 1/10$  measurement time
  - integrating circuit effectively faster, can improve S/N in same time and can reject interfering signals

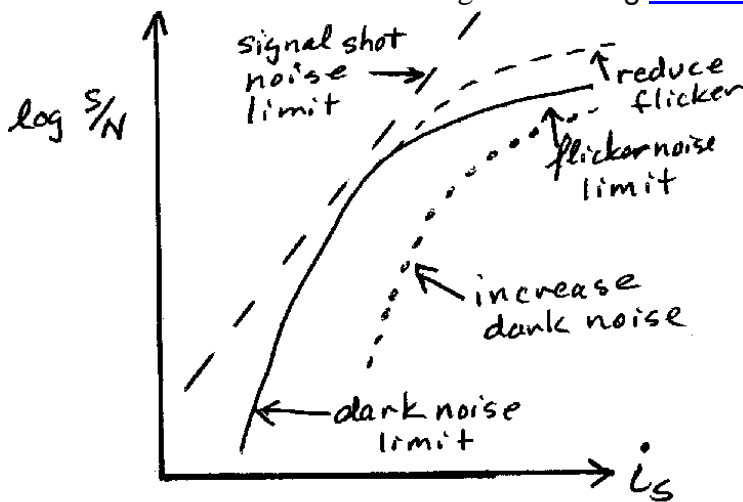
B. Quantum/shot noise -- square root dependence on signal level (also Schottky noise) due to random photon field and random probability of emission of  $e^-$  at interface

- PMT: signal depends on number of photons or photo electrons,  $n_p$   
 Signal:  $\phi = n_p$ , Noise:  $\sigma_p = n_p^{1/2}$ ,  $\rightarrow S/N = \phi / \sigma_p = n_p^{1/2}$ , ("pure" noise, intrinsic)
- cathode:  $(S/N)_n = n_c / \sigma_c = K n_p / (K n_p)^{1/2} = (K n_p)^{1/2}$ , in current:  $i_c / \sigma_c = (i_c t / e)^{1/2}$  ( $K \sim q \cdot \text{eff}$ )
- anode:  $\sigma_E = [2e\Delta f(1+\alpha)mGE]^{1/2}$ ,  $m$  - multiplier,  $G$  - gain in V/A,  $E$  - signal ( $R\phi$ ),  
 $\alpha \rightarrow$  multiplier adds to noise [vary 0.1-0.5, good PMT  $\sim (\delta-1)^{-1}$ ,  $\delta$  - gain per dynode]

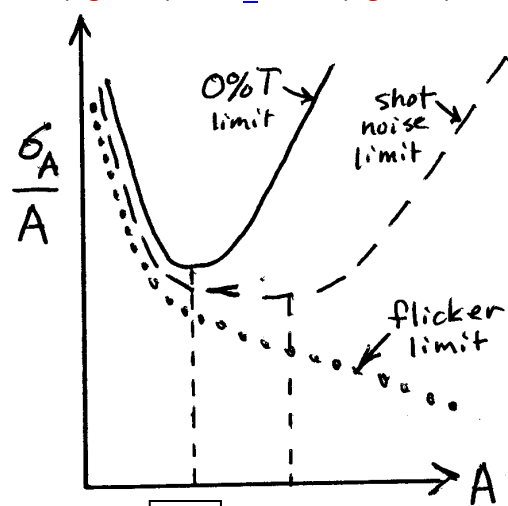
C. Other noise sources

1. Flicker, due to sample or blank variation - *non-fundamental*, plus especially source or temperature fluctuations  $\rightarrow$  impact the signal level, noise level  $\sim$  light signal:  $\sigma_F \sim E_S$
2. Dark current (e.g. field emission dynode or amplifier output level) -- excess noise, additive – independent of light level – note: not necessarily "white" can have spectrum
3. Quantization noise (finite digital resolution) – for  $q$  = quantization level, if  $\sigma > q/2 \rightarrow \sigma_q = q/12^{1/2}$  (if  $\sigma$  from other sources is less, then limit by readout resolution,  $\sigma_q = q/2$ )
4. Thermal (Johnson) noise - (thermal fluctuation of  $e^-$  in resistor)  $\sigma_J = (4kTR\Delta f)^{1/2} \rightarrow$ 
  - a. Effectively "white" (constant with  $f$ ) at practical detection frequencies
  - b. cooling, narrowing band pass help, smaller  $\sigma_J$  so less noise higher S/N
  - c. lowering  $R$  also, but usually costs signal (in volts)
5. Uncorrelated sources, sum the noise terms:  $N \sim [\sigma_e^2 + \sigma_F^2 + \sigma_q^2 + \sigma_J^2 + \dots]^{1/2}$ 
  - a. (read Section 5.4, 5.5)

D. Bottom line -- understand Figures relating  $S/N$  and  $E$  (fig. 5.6),  $A/\sigma_A$  vs  $A$  (fig. 5.7)



S/N Variations (Emission)



S/N variation (Absorption)

1. **Emission**—different noise sources approach the ideal shot-noise limit
  - a. Shot noise limit:  $S/N = i_s/[K(i_s+i_d)]^{1/2} \rightarrow K=2e\Delta f(1+\alpha)$  K-unit corr.,  $\alpha$ -PMT mult. noise  
—to improve  $\rightarrow$  reduce  $\Delta f$  and/or dark current,  $i_d$
  - b. Dark noise (or Signal) limit:  $S/N = i_s/(K i_B)^{1/2}$  - Add  $(X_{i_B})^2$  if flicker, *to improve inc. S*  
(or decrease dark noise by cooling detector or improving readout/amp or similar)
  - c. Flicker limit:  $S/N = \zeta^{-1}$  — becomes *constant S/N* at high S
2. **Absorption**—ratioing I and  $I_0$  makes more complex:  $\sigma_A = 0.43\sigma_T/T$  from  $A = -0.43 \ln T$ 
  - a.  $(S/N)^{-1} = \sigma_A/A = -\sigma_T/T \ln T$  --new form for plots (*inverse*), *lower is better* in this view
  - b. 0%T limiting conditions—dark or amp. or readout limited — min 0.43 A (**Fig wrong!**)  
reduce dark noise, IR this dominates—cool detector
  - c. Shot noise limited—min 0.87 A –reduce bandwidth, increase light level
  - d. Flicker—since constant, improves with absorbance, but *not real*,  
since losing light  $\rightarrow$  will become dark noise limited

## E. Enhance S/N

### 1. Filtering ---time domain

- a. **average** e.g. multiplex -- **time avg. idea**, integrate signals in each channel  
- multiple (n) scan average, increase  $S/N = n^{1/2}$
- b. **time constant**—attenuate the high frequency components to **enhance the DC**

### 2. Filter -- frequency domain (use $\Delta f$ - select signal, attenuate noise $\rightarrow$ bandpass or lock-in)

- a. best: digitize time varying signal, FT to frequency space (i.e.  $t \rightarrow \nu$  transform)
- b. multiply by  $H(f)$ , and back transform to signal representation,  $E(t)$

### 3. Adjust levels – i.e. change (increase) signal level or reduce noise level

- a. Shot-noise limit (raise to flicker limit),
- b. Dark limit (cool detector, get better amps, readout),
- c. flicker (**adjust instrument**, e.g. double beam -- counter drift, long time changes –  
measure signal and blank simultaneously)

### 4. Photon counting -- best for low light level -- $(S/N)_{PC}/(S/N)_i = [f_d(1+\alpha)]^{1/2}$ ,

- a.  $f_d$  discriminator coeff., fraction anodic pulses passed,
- b.  $(1+\alpha)$  term gives 5-25% improvement

### 5. Modulation -- demodulate with lock-in, boxcar, or correlation –

- a. Modulation can be major advantage when dark noise and 1/f noise limited—these are **additive** noise, not modulated, **independent of signal**, so **eliminated**
- b. all discriminate against noise which is broad band and no time correlation to signal (except flicker) - (**Fig. 5-9**)

## Homework

Discussion questions: Chap 5 - #5, 6, 7, 8, 9, 11, 13, 14, 15, 16, 19

To hand in: Chap 5 - #2, 4, 10, 17